Toshiba Intelligent Power Device Silicon Monolithic Power MOS Integrated Circuit

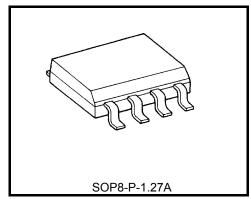
# **TPD1038F**

Motor, Solenoid, Lamp Drivers High-side Power Switch

The TPD1038F is a monolithic power IC for high-side switches. The IC has a vertical MOS FET output which can be directly driven from a CMOS or TTL logic circuit (e.g., an MPU). The device offers intelligent self-protection and diagnostic functions.

#### **Features**

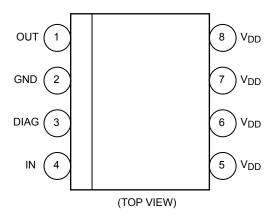
- A monolithic power IC with a structure combining a control block (Bi-CMOS) and a vertical power MOS FET on a single chip.
- One side of load can be grounded to a high-side switch.
- Can directly drive a power load from a microprocessor.
- Built-in protection against overheating and load short-circuiting.



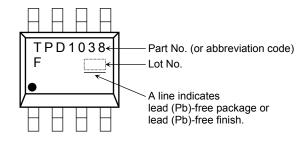
Weight: 0.08g(typ.)

- Incorporates a diagnosis function that allows diagnosis output to be read externally at load short-circuiting, opening, or overheating.
- Up to -(50-V<sub>DD</sub>) ~ -(60-V<sub>DD</sub>) of counterelectromotive force from an L load can be applied.
- Low on-resistance :  $R_{DS(ON)}=120 \text{m} \Omega \text{ (max)} \text{ ( @ V}_{DD}=12 \text{ V}, \text{ Ta}=25 ^{\circ}\text{C}, \text{ Io}=2 \text{ A)}$
- 8-pin SOP package for surface mounting that can be packed in tape

### **Pin Assignment**

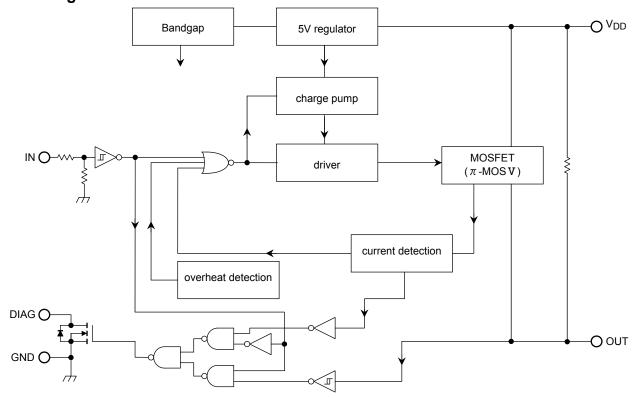


### Marking



Due to its MOS structure, this product is sensitive to static electricity.

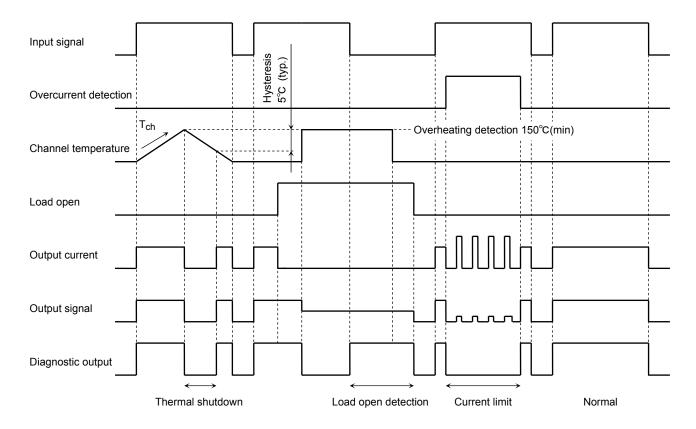
# **Block Diagram**



# **Pin Description**

Pin No.	Symbol	Function
1	OUT	Output pin. When the load is short-circuited and current in excess of the detection current (3A min) flows to the output pin, the output automatically turns on or off.
2	GND	Ground pin.
3	DIAG	Self-diagnosis detection pin.Goes low when overheating is detected or when output is short circuit with input on (high). N-channel open drain.
4	IN	Input pin. Input is CMOS compatible, with pull down resistor connected. Even if the input is open, output will not accidentally turn on.
5,6,7,8	V <sub>DD</sub>	Power pin.

# **Timing Chart**



3

# **Truth Table**

Input signal	Diagnosis output	Output signal	Output state	Operating state
Н	Н	Н	on	Normal
L	L	L	off	Nomial
Н	L	L	current limit (switching)	Load short
L	L	L	off	
Н	L	L	off	Overheating
L	L	L	off	Overneating
Н	Н	Н	on	Load open
L	Н	Н	off	Load open
Н	L	L	off	Overheating and
L	Н	Н	off	load open

# Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V <sub>DS</sub>	60	V
O	DC	V <sub>DD(1)</sub>	25	V
Supply voltage	Pulse	V <sub>DD(2)</sub>	$60(R_S=1\Omega,\tau$ =250ms)	V
	DC	V <sub>IN(1)</sub>	-0.5~12	V
Input voltage	Pulse	V <sub>IN(2)</sub>	V <sub>DD(1)</sub> +1.5(t=100ms)	V
Diagnosis output voltage		$V_{DIAG}$	-0.5~25	V
Output current	Output current		Internally limited	Α
Input current		I <sub>IN</sub>	±10	mA
Diagnosis current		I <sub>DIAG</sub>	5	mA
Power dissipation (Note 1-a)		P <sub>D(1)</sub>	1.1	W
Power dissipation (Note 1-b)		P <sub>D(2)</sub>	0.425	W
Operating temperature		Topr	<b>−40~110</b>	°C
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature		T <sub>stg</sub>	<b>−55~150</b>	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

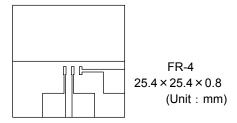
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Resistance**

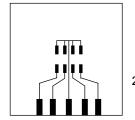
Characteristic	Symbol	Rating	Unit	
The annual manistra and	Du ( )	113.5 (Note1-a)	°C /W	
Thermal resistance	R <sub>th(ch-a)</sub>	294.0 (Note1-b)	C /VV	

Note 1:

1-a: Mounted on glass epoxy board (a)



1-b: Mounted on glass epoxy board (b)



FR-4

# Electrical Characteristics (T<sub>a</sub>=25°C)

Characteristics		Symbol	Test circuit	Test condition	min	typ.	max	Unit
Operating supply voltage		V <sub>DD(OPR)</sub>	_	_	6	12	18	V
Current dissipation	on	I <sub>DD</sub>	_	V <sub>DD</sub> =12V, V <sub>IN</sub> =0V, R <sub>L</sub> =10Ω	_	_	3	mA
H-level input volt	age	V <sub>IH</sub>	_	V <sub>DD</sub> =12V	3.5	_	_	V
L-level input volta	age	V <sub>IL</sub>	_	V <sub>DD</sub> =12V	_	_	1.5	V
H-level input current		lін	_	V <sub>DD</sub> =12V, V <sub>IN</sub> =5V	_	_	200	μΑ
On resistance		R <sub>DS(ON)</sub>	_	V <sub>DD</sub> =12V, I <sub>O</sub> =2A	_	_	0.12	Ω
Output leakage o	urrent	l <sub>OL</sub>	_	V <sub>DD</sub> =12V	_	_	1	mA
Diagnosis output voltage	"L"-level	V <sub>DL</sub>	_	$V_{DD}$ =12V, $V_{IN}$ =0V, $I_{DL}$ =1mA $R_L$ =10 $\Omega$	_	_	0.4	V
Diagnosis output current	"H"-level	IDH	_	$V_{DD}$ =12V, $V_{IN}$ =5V, $R_L$ =10 $\Omega$ , $V_{DH}$ =12V	_	_	10	μΑ
		I <sub>OC(1)</sub> (Note2)	1,2	V <sub>DD</sub> =12V	3	_	9	Α
Over current dete	Over current detection		3	V <sub>DD</sub> =12V, R <sub>L</sub> =0.1 Ω	_	_	10	Α
Overheating dete	Overheating detection		_	V <sub>DD</sub> =12V	150	_	200	°C
Load open detection (Note4)		R <sub>op</sub>	_	V <sub>DD</sub> =12V, V <sub>IN</sub> =0V	5	17	_	kΩ
Switching time		t <sub>on</sub>	4	V <sub>DD</sub> =12V, R <sub>L</sub> =10 Ω	-	-	100	μs
		t <sub>off</sub>			_	_	40	μs
Diagnosis delay time		t <sub>DLH</sub>	DLH 5	$V_{DD}$ =12V, R <sub>I</sub> =10 $\Omega$	_	70	_	μs
		t <sub>DHL</sub>	-	VDD 124,112 10 32	_	22	_	μs
Output clamp voltage		V <sub>clamp</sub>	_	V <sub>DD</sub> =12V, V <sub>IN</sub> =0V, I <sub>O</sub> =1A, L=10mH	-(60- V <sub>DD</sub> )	_	-(50- V <sub>DD</sub> )	V

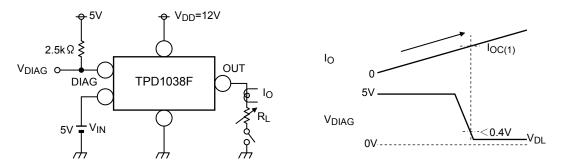
(Note 2) Over-current detection

(Note 3) Peak current @ current limit function

(Note 4) Load open detection function :  $V_{DD}$  = 8  $\sim$  18V

### **Test Circuit 1**

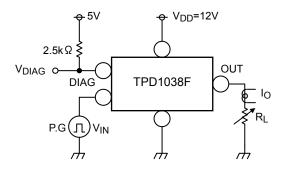
Over current detection I<sub>OC(1)</sub> : Over current detection when load current is increased while VIN = "H"

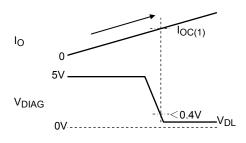


2006-10-31

### **Test Circuit 2**

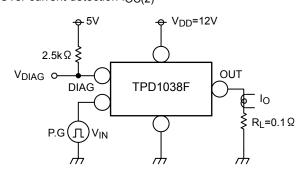
Over current detection  $I_{OC(1)}$  : Over current detection when load is short circuit and VIN = "L"  $\rightarrow$  "H"

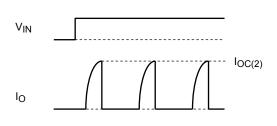




### **Test Circuit 3**

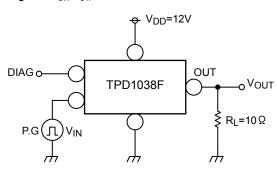
Over current detection IOC(2)

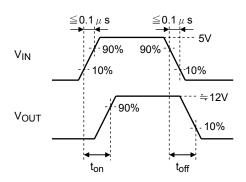




## **Test Circuit 4**

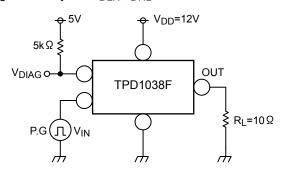
Switching time ton, toff

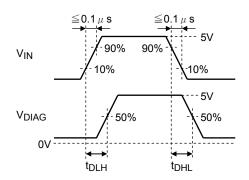


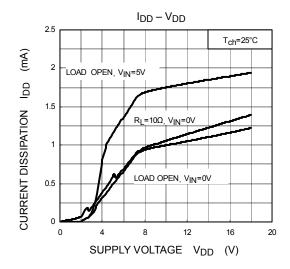


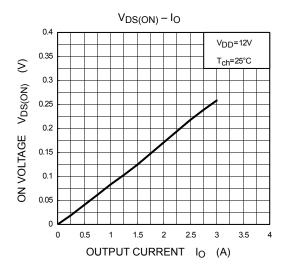
#### **Test Circuit 5**

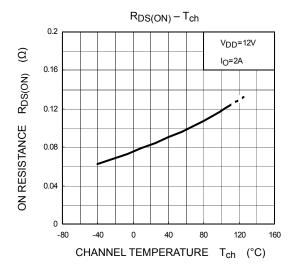
Diagnosis delay time t<sub>DLH</sub>, t<sub>DHL</sub>

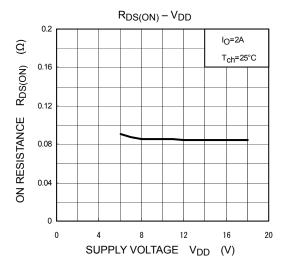


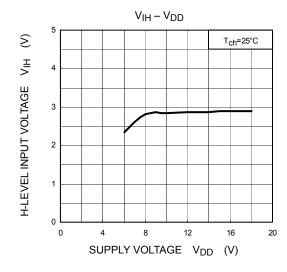


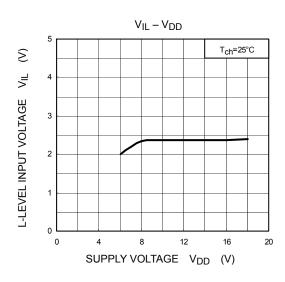


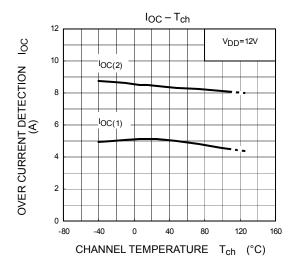


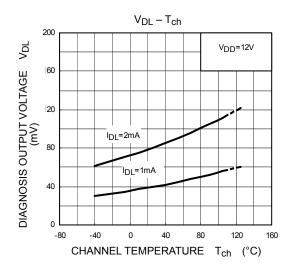


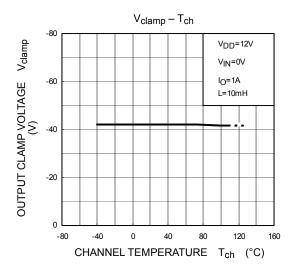


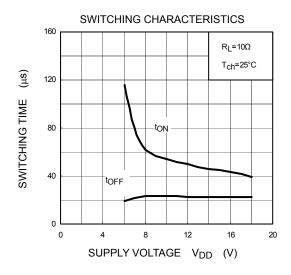


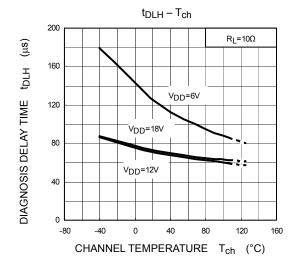


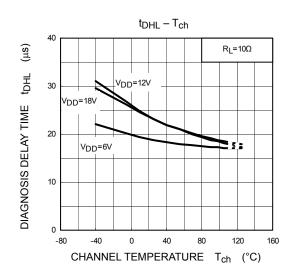


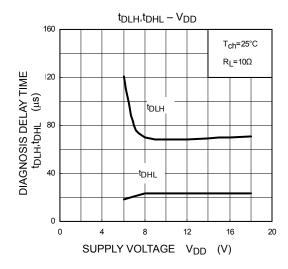


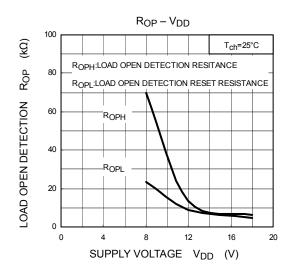


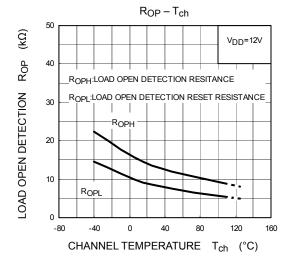


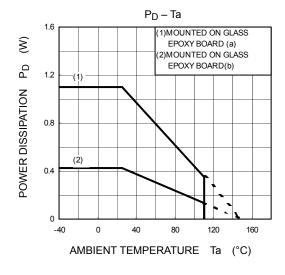


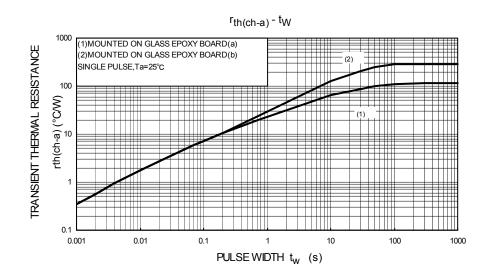




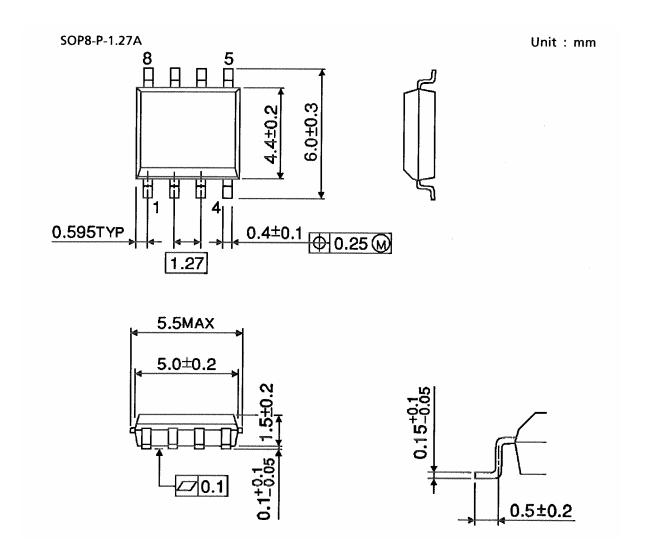








# **Package Dimensions**



Weight: 0.08g (typ.)

10 2006-10-31

### **RESTRICTIONS ON PRODUCT USE**

20070701-EN

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any patents or other rights of TOSHIBA or the third parties.
- Please contact your sales representative for product-by-product details in this document regarding RoHS
  compatibility. Please use these products in this document in compliance with all applicable laws and regulations
  that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses
  occurring as a result of noncompliance with applicable laws and regulations.